

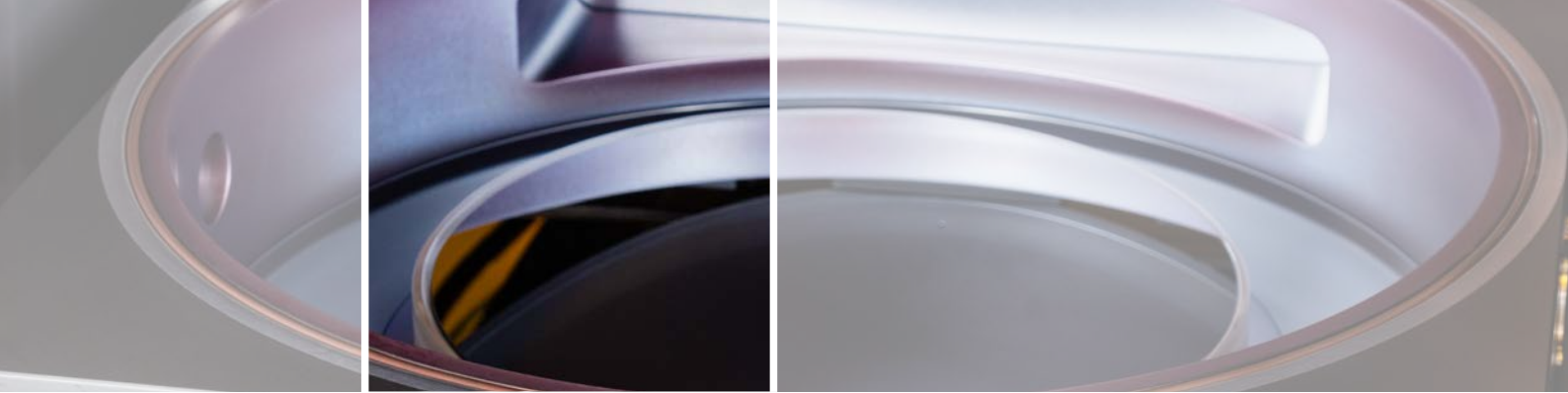


AUTOMATED WAFER BONDING PLATFORM

## **SUSS XBS300**

**Permanent bonding platform for 300mm hybrid fusion bonding**





## AUTOMATED WAFER BONDING PLATFORM

# SUSS XBS300

## Hybrid bonding platform

**The universal XBS300 platform is designed for hybrid fusion bonding of aligned 200 mm and 300 mm wafers. Its highly modular design offers maximum configuration flexibility at low cost-of-ownership for customers. Different configurations are available to meet requirements of both R&D and high-volume manufacturing (HVM).**

Hybrid bonding as an extension of conventional fusion bonding is a key enabler for the future heterogeneous integration market with respect to advanced 3D device stacking, e.g. for next generation memory or demanding SoC (System on Chip) applications such as backside illuminated CMOS image sensors.

The system allows for both collective die-to-wafer (D2W) and wafer-to-wafer (W2W) bonding schemes and is therefore a versatile platform for "More-than-Moore" devices.

### MATERIAL HANDLING UNIT

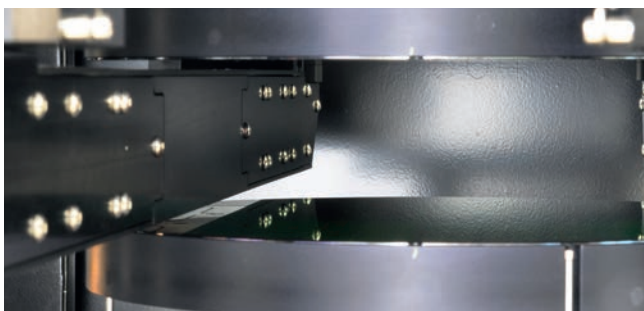
The XBS300 platform can be equipped with up to four load ports, one bond aligner and up to six process modules addressing potential needs for HVM.

A high-precision and high-throughput 6-axis-robot handles single wafers and bonded wafer stacks. A fully customizable camera configuration monitors all handling or processing activities inside of the platform.



### HIGHLIGHTS

- + Fully automated fusion and hybrid wafer bonder for D2W and W2W applications on 200 mm and 300 mm wafers in a single platform
- + High-accuracy alignment option for most demanding pitch applications (<100 nm overlay)
- + Integrated metrology option including overlay measurement, void detection and TTV measurement (for D2W), allowing for multi-point measurement at highest accuracy

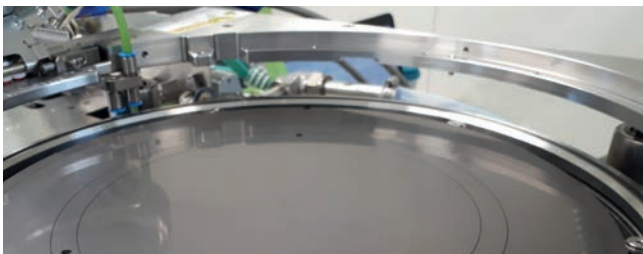


### BOND ALIGNER

The bond aligner delivers consistent alignment accuracy for transparent or non-transparent wafers by using the SUSS proprietary Inter-Substrate Alignment (ISA) technology. Built-in optical fixed reference, global calibration and overlay verification ensure optimum repeatability. Global calibration wafers are an integral part of the system providing fast and easy automated calibration and overlay verification. In order to address current and future needs for pitch-scaling of interconnects the bond aligner offers <100 nm overlay capa-



## Process modules for flexible configuration possibilities



### LOW FORCE BOND CHAMBER

Some processes require additional bond force to be applied during annealing. The low force bond chamber produces up to 15 kN of bond force at temperatures of up to 250 °C. An optional cool plate for active wafer cooling can be installed in the same process module.



### METROLOGY MODULE

Integrated in-situ metrology functionality allows for fast process feedback. The metrology module is therefore key for increased process control and yield improvement. The module can be configured for full-field IR void inspection and/or IR overlay measurement featuring multi-site capability at high throughput. In-line process control via closed-loop feedback allows to optimize the overlay performance.



### PLASMA CHAMBER

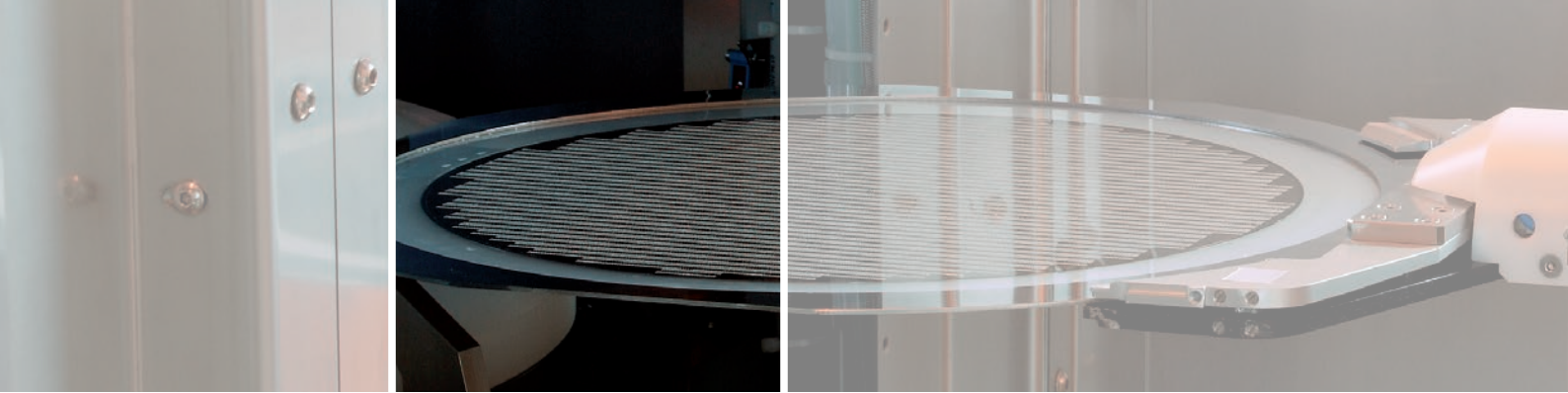
The module offers highest process flexibility and repeatability for plasma-based wafer surface activation. Various process gases such as Ar, O<sub>2</sub>, N<sub>2</sub> etc. can be used and are controlled via mass flow controllers (MFCs). The gate-valve loading plasma chamber allows for full CMOS compatibility and can also be used for plasma cleaning of polymer resi-



### AQUEOUS CLEANER

The aqueous cleaner module offers various processing options including megasonic assisted DI water cleaning. The module is compatible with diluted cleaning chemistry such as <2% NH<sub>4</sub>OH and offers optional backside rinse and N<sub>2</sub> assisted spin-drying. Organic removal functionality





## Media cabinet

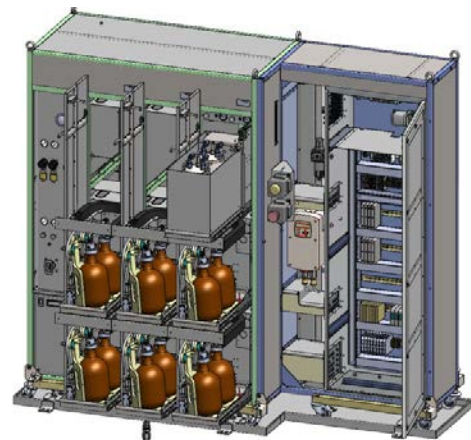
### Flexibility for different process requirements

#### MEDIA CABINET III EX

The Media Cabinet III Ex is designed for the use in an EX Zone 1. The media cabinet consists of two main parts, the media part and the pressurized electrical cabinet.

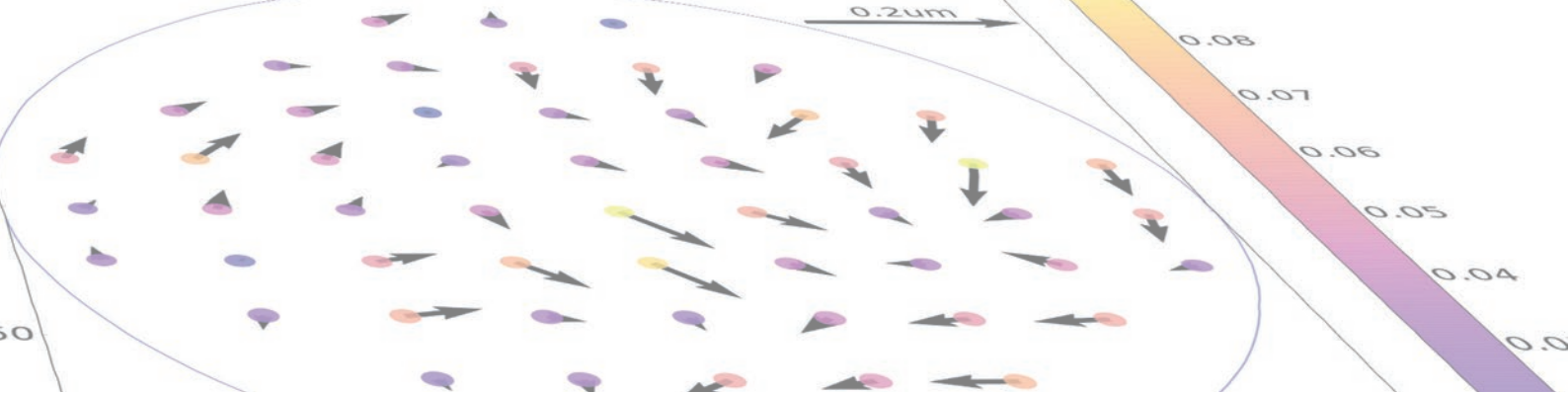
Part of the wafer processing process is the media management. The medias are house-supplied and stored in buffer tanks inside the media cabinet. This guarantees a continuous supply. Each tank system consists of two tanks with a switch over system. If one tank is empty, the second will be used and the first will be filled again.

In the cabinet are also switchable bottles arranged. The bottle change will be done manually. This guarantees also a continuous supply. The switch over is based on a Venturi suck system and an additional reservoir. The media transport to the process modules is done by a pneumatic transfer system. The delivery pressure of the system can be adapted to the viscosity of the media.



*Media Cabinet III Ex for media management*





# SUSS XBS300

## Technical data

### MATERIAL HANDLING UNIT

<b>Substrate Size</b>	200 / 300 mm wafers
<b>Frame Options</b>	Optimized configurations available allowing low footprints both for R&D and high-volume manufacturing
<b>Load Port</b>	Fully automatic FOUP load ports and cassette adapter options (up to 4 loadports)
<b>Wafer Handling System</b>	6-axis robot with integrated wafer flipping Special handlers (e.g. for warped wafers) on request
<b>Pre-Aligner and ID readers</b>	Camera-based pre-aligner and optional wafer ID reader
<b>User Interface</b>	Microsoft Windows10-based operating system with SUSS MMC software
<b>Substrate Processing</b>	Fully programmable cluster tool with factory automation options Drag and drop sequence editor with cyclic scheduler and automated throughput optimization
<b>Options</b>	SECS/GEM and different data logging/analyzing tools Ionizer bars

### BOND ALIGNER

<b>General</b>	Vibration-isolated alignment stage with contact-less linear motors and air bearings for x, y, z and theta axes Active wedge error compensation function and active isolated granite base structure
<b>Alignment Method</b>	Inter-Substrate Alignment (ISA) with integrated fixed reference targets, built-in global calibration and overlay verification Reflective IR alignment available on request Closed-loop feedback (from metrology module) for automatic offset-correction
<b>Alignment Accuracy</b>	< 50 nm
<b>Overlay Accuracy</b>	< 400 nm (3 sigma) default setup < 100 nm (3 sigma) optional

### PLASMA MODULE

<b>General</b>	Plasma chamber for effective wafer surface activation for (hybrid) fusion bonding
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### BOND CHAMBER

<b>Bond Processes</b>	Low-force thermo-compression bonding, adhesive bonding and vacuum fusion bonding
<b>Maximum Temperature</b>	Up to 250 °C
<b>Base Vacuum Minimum</b>	< 5 mbar
<b>Pumpdown</b>	< 60 sec
<b>Bond Force (@ 300mm)</b>	1 kN - 15 kN
<b>Process Gas</b>	N <sub>2</sub> , optional 1 MFC
<b>Bond Alignment</b>	Center-to-center alignment: +/- 50 μm Notch rotation: 0.1°

### COOL PLATE

<b>Cool Plate Temperature</b>	15 - 30 °C
<b>Temperature Control</b>	± 0.2 °C
<b>Cooling Method</b>	Programmable proximity with fixed minimum proximity

### AQUEOUS CLEANER

<b>General</b>	Single wafer cleaner with puddle and megasonic DIW rinsing Diluted chemistry (e.g. < 2% NH <sub>4</sub> OH) possible
<b>Options</b>	Back-side rinse N <sub>2</sub> assisted spin-dry SC1 chemistry compatibility

### DETACH STATION

<b>General</b>	Wafer chuck with lift-pins, sealing lip and heater for up to 200 °C Wafer lifting device
<b>Options</b>	Wafer rework option for defect-free separation of pre-bonded wafer stacks

### METROLOGY MODULE

<b>General</b>	Throughput- and footprint-optimized metrology station for high-accuracy overlay measurement and optional void detection Field-upgradable
<b>Measurement Flexibility</b>	No restriction on location or amount of measurement sites on wafer

### METROLOGY OPTIONS

<b>IR Overlay Measurement</b>	Reflective or transmissive mode
<b>IR Void Detection</b>	Automated classification and localization logging
<b>TTV Measurement</b>	Interferometric film thickness measurement

Data, design and specification depend on individual process conditions and can vary according to equipment configurations. Not all specifications may be valid simultaneously. Illustrations, photos and specifications in this brochure are not legally binding. SUSS MicroTec reserves the right to change machine specifications without prior notice.



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